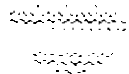


APPENDIX

APPENDIX A

ACRONYMS

APL	Approved Parts List
ATE	Automatic Test Equipment
BIT	Built-In Test
CAI	Computer-Aided Design
CA	Computer-Aided Manufacturing
CD	Critical Design Review
CN	Complimentary Metal Oxide Semiconductor
Da	Department of Defense
DPA	Destructive Physical Analysis
DSARC	Defense Systems Acquisition Review Council
DSB	Defense Science Board
DT	Development Test
DT&E	Development Test and Evaluation
ECP	Engineering Change Proposal
ESS	Environmental Stress Screening
FOT&E	Follow-on Operational Test and Evaluation
FRACAS	Failure Reporting, Analysis, and Corrective Action System
FSD	Full-Scale Development
GAO	General Accounting Office
IES	Institute of Environmental Sciences
ILS	Integrated Logistics Support
IMIP	Industrial Modernization Incentive Program
IOT&E	initial Operationat Test and Evaluation
IPF	Initial Production Funds
ISD	Instructional Systems Development
ITP	Integrated Test Plan
JMSNS	Justification for Major System New Start



LOL	Loss of Learning
LSA	Logistics Support Analysis
MFHBF	Mean Flight Hours Between Failure
MTBF	Mean Time Between Failure
MIL-HDBK	Military Handbook
MIL-SPEC	Military Specification
MIL-STD	Military Standard
NOSC	Naval Ocean Systems Center
NWC	Naval Weapons Center
OSD	Office of the Secretary of Defense
OT	Operational Test
PAT	Production Acceptance Test
PCB	Printed Circuit Board
PIN	Particle Induced Noise
PPBS	Planning, Programming, and Budgeting System
PRR	Production Readiness Review
RDT&E	Research, Development, Test, and Evaluation
RFP	Request for Proposal
s o w	Statement of Work
STE	Special Test Equipment
TAAF	Test, Analyze and Fix
T&E	Test and Evaluation
TEMP	Test and Evaluation Master Plan
TPS	Test Program Set
TTL	Transistor/Transistor Logic
USDR&E	Under Secretary of Defense for Research and Engineering

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